Applicant's Substitute for 1449A'

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Complete if Known 09/870 332 **Application Number** Filing Date -30-01 SHEPARD, Chester L. First Named Inventor **Group Art Unit** Examiner Name Attorney Docket Number 50005-20

of

U.S. PATENT DOCUMENTS								
Examiner Initials	Cite No. <sup>1</sup>	U.S. Patent Document  Kind Code Number pt Inneuro	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear			
5V		4,043,780	Bricker et al.	08/23/1977				
4V		4,185,982	Schwenninger	01/29/1980				
ZV		4,578,102	Colmon et al.	03/25/1986				
51		4,888,038	Herrington et al.	12/19/1989				
N		5,279,635	Flaugher et al.	01/18/1994				
SV		5,330,549	Carlomagno et al.	07/19/1994				
A		5,332,316	Kleinerman	07/26/1994				
3		5,730,528	Allison et al.	03/24/1998				
SV		5,735,922	Woodward et al.	04/07/1998				
37		5,846,281	Nikander et al.	12/08/1998				
3V		5,931,981	McMaster et al.	08/03/1999				
CV		5,938,810	DeVries, Jr. et al.	08/17/1999	,			
<b>3</b> V		6,079,227	Yoshizawa et al.	06/27/2000	7			
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FOREIGN PATENT DOCUMENTS								
Examiner Initials*	Cite No.	Foreign Patent Document			None of Debugge as Australa	Date of Publication of	Pages, Columns, Lines, Where	
		Office <sup>2</sup>		Name of Patentee or Applicant of Cited Document	TI Cited Document MM-DD-YYYY	Relevant Passages or Relevant Figures Appear	τ°	
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			ATTY, DOCKET NO. 50005-20	SERIAL NO.			
INFOR	MAT	ION DISCLOSURE CITATION					
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7	) Posou	DUCTION OF PTO FORM 1449	SHEPARD, Chester L. et al.				
UUL 2 0 2001	Tr KO	DOCTION OF FIO PORM 1449	FILING DATE	GROUP			
3410/	C	THER DOCUMENTS (Including Author	or, Title, Date, Pertinent Page	es, Etc.)			
	/	Mann D. and Viskanta R., An Inverse Method for Determining Transient Temperature Distribution in Glass Plates, Inverse Problems in Engineering, vol. 1, pp. 273-291					
50		auss Flates, Involce Froberts at Engine	sing, voi. 1, pp. 270-201				
4		Weber, M.J., Radiative and Multiphonon Relaxation of Rare-Earth lons in Y <sub>2</sub> O <sub>3</sub> , The Physical Review,					
٧		Vol. 171, No. 2 July 10, 1968					
		Risebert, L.A. and Moos, H.W., Multiphone	on Orbit-Lattice Relaxation of Exc	ited States of Rare-Earth			
$\mid SV \mid$		lons in Crystals, The Physical Review, Vol	I. 174, No. 3 October 10, 1968				
		Maurice, Eric; Wade, Scott A.; Collins, Ste					
SV	/	referenced Point Temperature Sensor Bas Fiber, Applied Optics, Vol. 36, No. 31 Nov		Ratio in Yb3+-doped Silica			
		Glebov, L.B. and Boulos, E.N., Absorption					
1 SU		Selection of Intrinsic, Ferric, and Ferrous S Crystalline Solids 242, pp. 49-62 (1998)	Specifa in the visible and DV neg	ions, Journal of Non-			
				-			
4		Collins, S.F., Baxter, G.W. and Wade, S.A., Comparison of Fluorescence-based Temperature Sensor Schemes: Theoretical Analysis and Experimental Validation, Journal of Applied Physics, Vol. 84 No. 9 November 1 1998					
		5 110 tember 1 1000	<del></del>				
		Proceedings of the FY 1999 glass Industry	Project Review, September 13-	14, 1999			
5V		·					
		Wade, S.A., Muscat, J.C., Collins, S.F. and					
(5)		Sensor Using the Fluorescence Intensity F No. 11 November 1999	nalio Techniques, Heview of Scie	ntific instruments, voi. 70,			
70							
51)		Wade, S.A., Baxter, G.W. and Collins, S.F Fluorescence from Yb-doped Silica Fiber,					
		The second of th	None of Colorland Maturicine,	701. 7 1, 110. 0 dane 2000			
51/		Grattan, K.T.V. and Zhang, Z.Y., Fiber Op	tic Fluorescence Thermometry, C	hapter 1			
	1						
EXAMINER DATE CONSIDERED 7-7				-71-03			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through							
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